# 150V N-Channel PowerTrench<sup>o</sup> MOSFET

# **General Description**

FAIRCHILD SEMICONDUCTOR

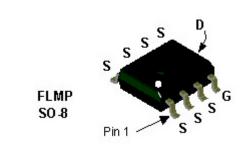
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low  $R_{DS(ON)}$  in a small package.

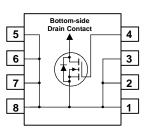
# Applications

- Synchronous rectifier
- DC/DC converter

# Features

- 4.1 A, 150 V.  $R_{DS(ON)} = 78 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$  $R_{DS(ON)} = 88 \text{ m}\Omega @ V_{GS} = 6.0 \text{ V}$
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability
- Fast switching, low gate charge (38nC typical)
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





# Absolute Maximum Ratings T<sub>A=25°C</sub> unless otherwise noted

Symbol	Parameter		Ratings	Units	
V <sub>DSS</sub>	Drain-Source Voltage			150	V
V <sub>GSS</sub>	Gate-Source Voltage			± 20	
I <sub>D</sub>	Drain Curren	t – Continuous	(Note 1a)	4.1	A
		– Pulsed		30	
P <sub>D</sub>	Power Dissip	bation for Single Operation	(Note 1a)	3.0	W
			(Note 1b)	1.8	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		rature Range	-55 to +150	°C
Therma	Charact	eristics			
				10	
R <sub>θJA</sub>	Thermal Res	sistance, Junction-to-Ambie	nt (Note 1a)	40	°C/W
R <sub>eJA</sub> R <sub>eJC</sub>	Thermal Res		nt (Note 1a) (Note 1)	40 0.5	°C/W
R <sub>θJA</sub> R <sub>θJC</sub>	Thermal Res Thermal Res	sistance, Junction-to-Ambie	(Note 1)		°C/W
R <sub>eja</sub> R <sub>ejc</sub> Packag	Thermal Res Thermal Res	istance, Junction-to-Ambie istance, Junction-to-Case	(Note 1)		Quantity

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	urce Avalanche Ratings					
W <sub>DSS</sub>	Drain-Source Avalanche Energy	Single Pulse, $V_{DD}$ = 150 V, $I_D$ = 10 A L = 8.8 mH			440	mJ
I <sub>AR</sub>	Drain-Source Avalanche Current				10	А
Off Char	acteristics					
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS}=0~V, \qquad I_D=250~\mu A$	150			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 µA, Referenced to 25°C		154		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 120 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
I <sub>GSS</sub>	Gate–Body Leakage	$V_{GS}=\pm~20~V,~V_{DS}=0~V$			±100	nA
On Chara	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	2	2.6	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$		-7		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$ \begin{array}{ll} V_{\rm GS} = 10 \; V, & I_{\rm D} = 4.1 \; A \\ V_{\rm GS} = 6.0 V, & I_{\rm D} = 3.8 \; A \\ V_{\rm GS} = 10 \; V, & I_{\rm D} = 4.1 \; A, T_{\rm J} = 125^{\circ} C \end{array} $		57 60 111	78 88 160	mΩ
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V},  I_D = 4.1 \text{ A}$		24		S
Dvnamic	Characteristics					
Ciss	Input Capacitance	$V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V},$		1884		pF
Coss	Output Capacitance	f = 1.0 MHz		102		pF
Crss	Reverse Transfer Capacitance			35		pF
R <sub>G</sub>	Gate Resistance	$V_{GS} = 15 \text{ mV}, \text{ f} = 1.0 \text{ MHz}$		1.6		Ω
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn–On Delay Time	$V_{DD} = 75 V, I_D = 1 A,$		10	20	ns
t <sub>r</sub>	Turn–On Rise Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		6	12	ns
t <sub>d(off)</sub>	Turn–Off Delay Time			40	64	ns
tr	Turn–Off Fall Time			20	36	ns
Qg	Total Gate Charge	$V_{DS} = 75 \text{ V}, \ I_D = 4.1 \text{ A},$		38	53	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		8		nC
Q <sub>gd</sub>	Gate-Drain Charge			11		nC
Drain-Sc	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain–Sourc				2.5	А
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V, I_S = 2.5 A$ (Note 2)		0.75	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 4.1A		75		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A}/\mu \text{s}$ (Note 2)		404		nC



Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

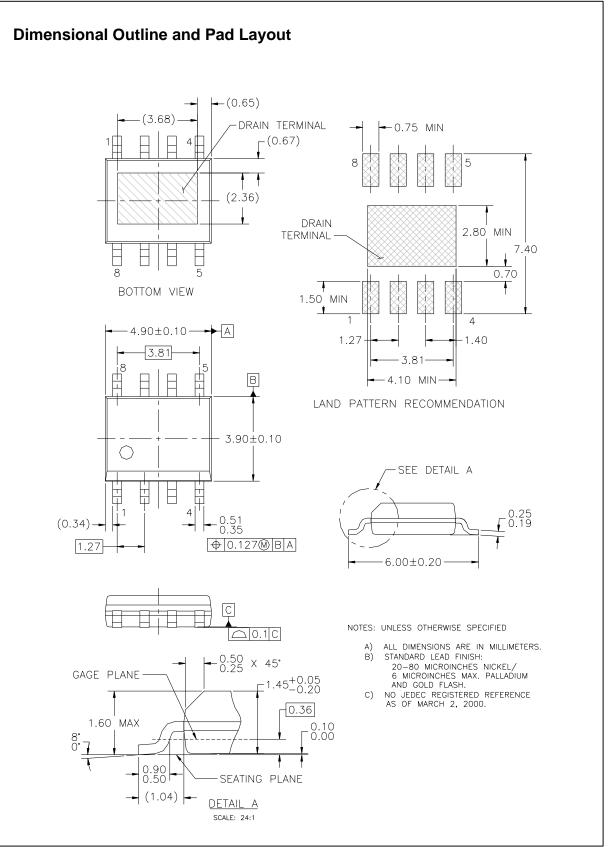
a) 40°C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper

66.00

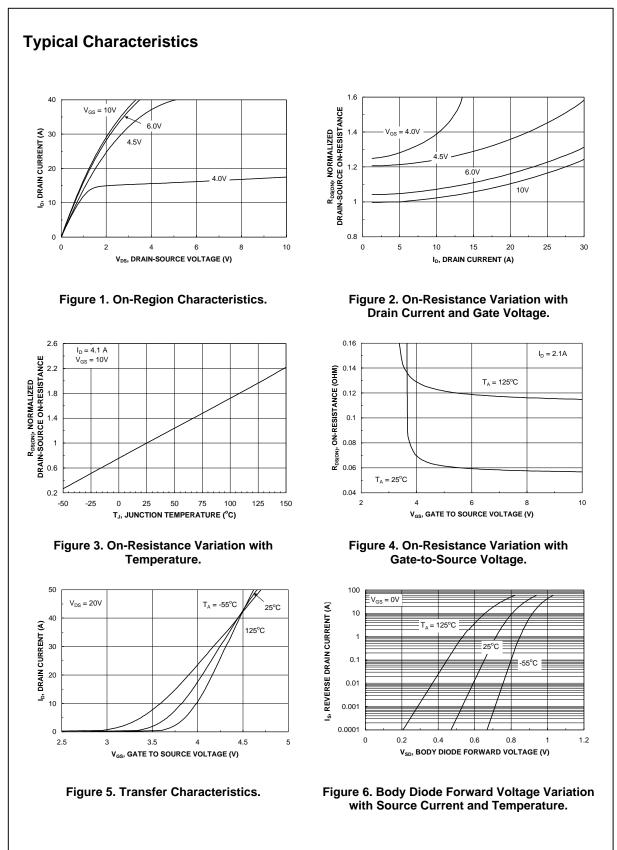
85°C/W when mounted on a minimum pad of 2 oz copper

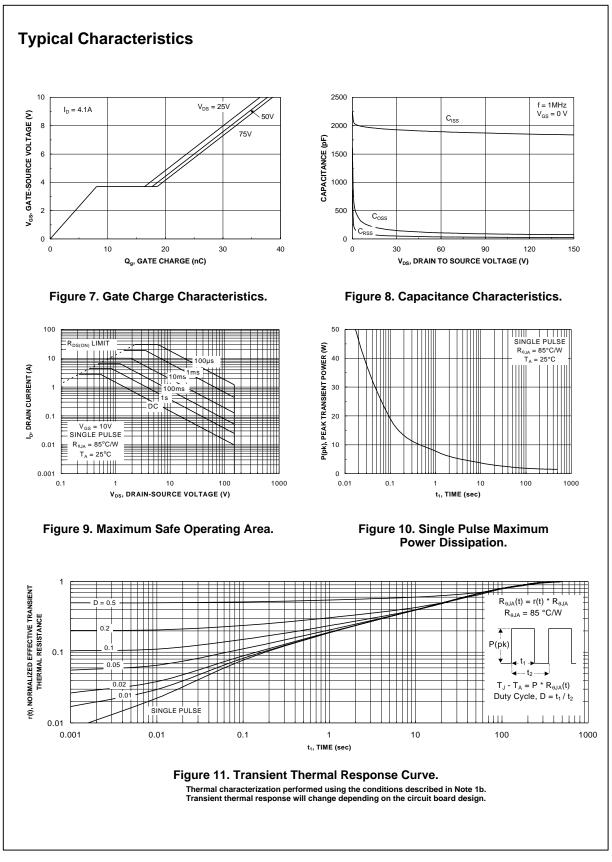
FDS2070N7 Rev D(W)

FDS2070N7



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